LINEAR TECHNOLOGY

RELIABILITY DATA

LTC987 LTC1726/27/28 LTC1921/85 LTC2900/01/02/23 LTC4257

9/26/03

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS (1) AT +125°C	NUMBER OF (2) FAILURES
SOIC/SOT/MSOP	589	9914	0322	487.64	0
SSOP/TSSOP	231	0213	0318	231.00	0
	820			718.64	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	1,182	9924	0252	204.80	0
	1,182			204.80	0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	4,947	9924	0252	850.68	0
	4,947			850.68	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	1,143	9924	0252	510.35	0
	1,143			510.35	0

(1) Assumes Activation Energy = 0.7 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 16.47 FITS

(3) Mean Time Between Failures in Years = 6,926

Note: 1 FIT = 1 Failure in One Billion Hours.